



2008 Workshop on Accelerated Stress Testing & Reliability

“Achieving Cradle to Grave Reliability using DFR and Accelerated Stress Testing”

October 1 – 3, 2008

Portland, OR

Over the last few years, Accelerated Stress Testing (AST) has been embraced by an ever widening array of worldwide companies seeking to reconcile the need for the highest quality product with the necessary push for early time-to-market. The purpose of the AST Workshop is to share ideas on better ways of accelerating and detecting hidden defects, flaws, and weaknesses in electronic and electro-mechanical hardware that would result in failures during usage. These techniques are focused on testing electronic hardware to destruction limits and root cause investigation to determine the physics-of-failure. The goal of AST is to produce mature products at market introduction and, in making it robust, the product can be screened for manufacturing defects with high combined stresses (beyond end-use specifications) for shorter lengths of time.

Sponsored by the [IEEE/CPMT ASTR](#) Committee and Technically co-sponsored by the [IEEE Reliability Society](#)

CALL FOR PAPERS

PAPER TOPICS (Papers submitted should be on topics related to the theme. Some examples of topics related to the theme are listed below):

- DFR Techniques and Practices
- Accelerated Life Testing
- Test Strategies for Maximum Reliability
- Hardware Reliability Improvements and Associated Success Stories
- Reliability in Nanotechnology Applications
- Reliability in IC Packages
- Accelerated Life Tests for Predicting Tin Whisker Problems
- Tin Whisker Mitigation Strategies
- New / Improved Methodologies of Component and System Accelerated Life Testing
- Design and Accelerated Test Methods to Achieve Reliability in Vehicular Technologies
- Stress Test and Quality Excursion Management in Outsource Manufacturing Environments
- Design and Accelerated Test Methods to Achieve Reliability in Alternate Energy Applications – Solar Collectors, Wind Turbines, Tide Generators, etc.
- Design and Accelerated Test Methods to Achieve Reliability in Space Applications
- Physics of Failure
- Failure Analysis
- Reliability Modeling and Simulation
- Reliability Prediction Correlated to Accelerated Life Testing
- Accurate Reliability Prediction using 217Plus and other Methods
- No Fault Found Issues – Location and Elimination
- Pneumatic Vibration versus Electrodynamical Vibration Stress Testing

IMPORTANT DATES

Abstract Deadline	Feedback Provided	Completed Paper Deadline	Notification of Acceptance	Camera Ready Paper Deadline
15 May 2008	30 May 2008	13 June 2008	14 July 2008	15 August 2008

TECHNICAL PROGRAM CHAIR

Don Gerstle
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SESSION CHAIRS (Please email your abstract submission to the appropriate Session Chair):

Keynotes/Tutorials

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For all workshop information, please visit the ASTR website:

<http://www.ewh.ieee.org/soc/cpmt/tc7/ast2008/>

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